

10 psec Time-Of-Flight Counter

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Points for TOF counter
Photo-detector
Measurements - Beam tests
New Approaches
Know-how

1. Points for TOF counter/

Photo-detectors

(Transit Time Spread) TTS

Multi-anode linear-array PMT (L16 & L24)

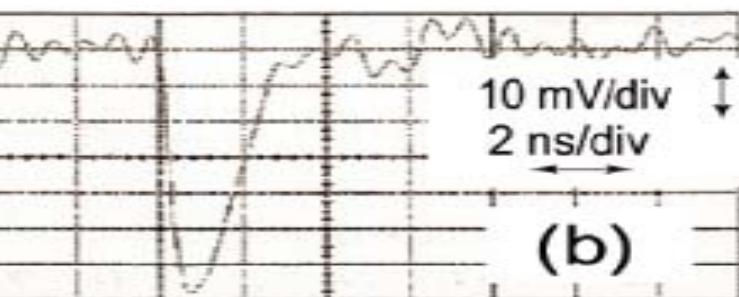
70-80; 120 ps

Hybrid Avalanche Photo-Diode

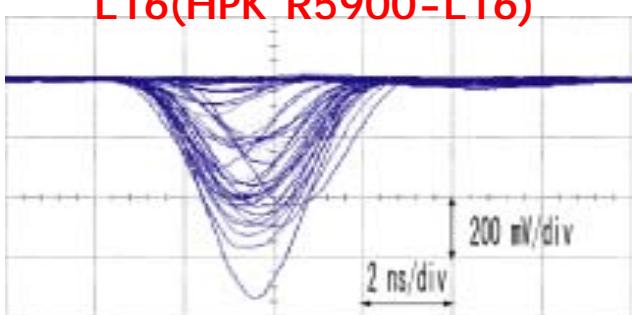
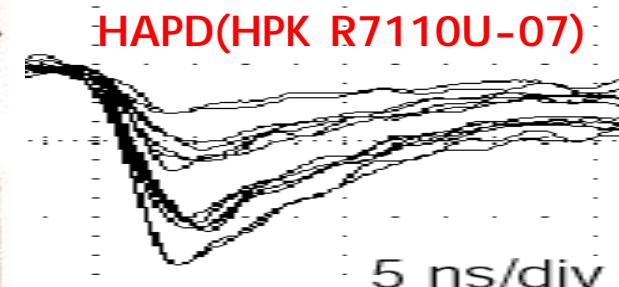
150 ps

Micro-Channel-Plate PMT

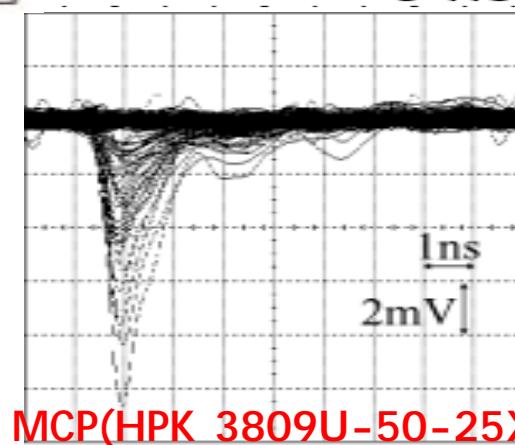
30-40 ps



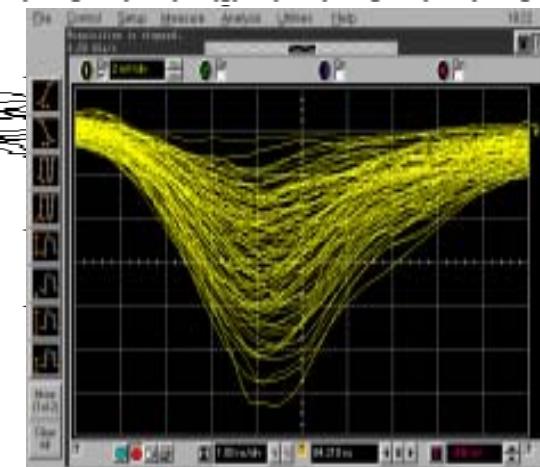
HAPD(HPK R7110U-07)



L24(HPK R6135-L24X)



MCP(HPK 3809U-50-25X)



PMT(HPK H7195)
1 ns/div

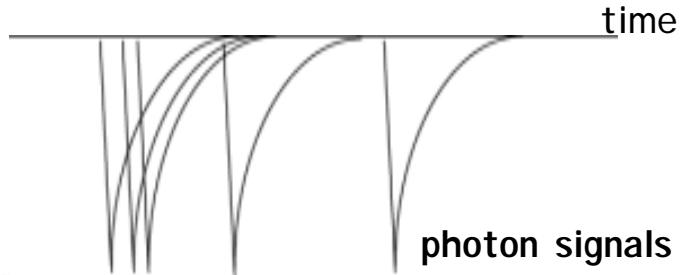
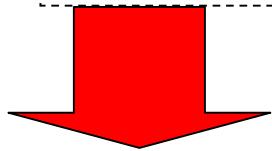
Footnote: これまで開発研究した光検出器の1光子に対する信号と測定TTS。信号の立ち上がりの速さを比較せよ。

1. Points for TOF counter

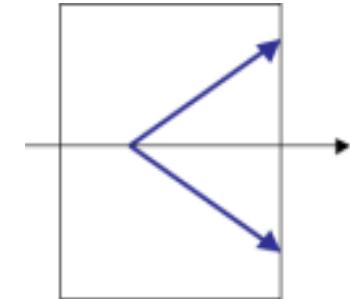
Fluctuations of

1. TTS
2. Decay-time ($T_d \leq TTS$)
3. Light-path ($T \leq TTS$)
4. N

Photo-statistics $1/\sqrt{N}$ is varied only at $T_d, T \ll TTS$.



quartz: $n=1.47$;
 $\theta=45^\circ$ (for GeV/c particles)



1. 30-40 ps (MCP-PMT), 70-80 ps (L16)

2. Cherenkov light

3. Normal incidence

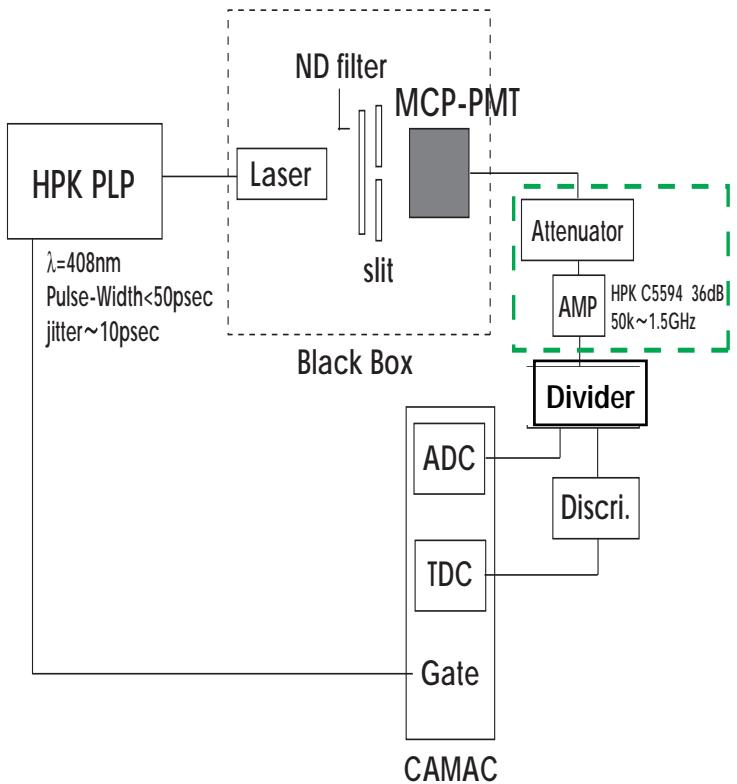
$$\sigma = (30 \times 2 - 30) \text{ ps} / 1 \text{ cm} / (\sqrt{12N}) = 9 \text{ ps} / \sqrt{N} / 1 \text{ cm}$$

4. 50 detected photons/1 cm quartz

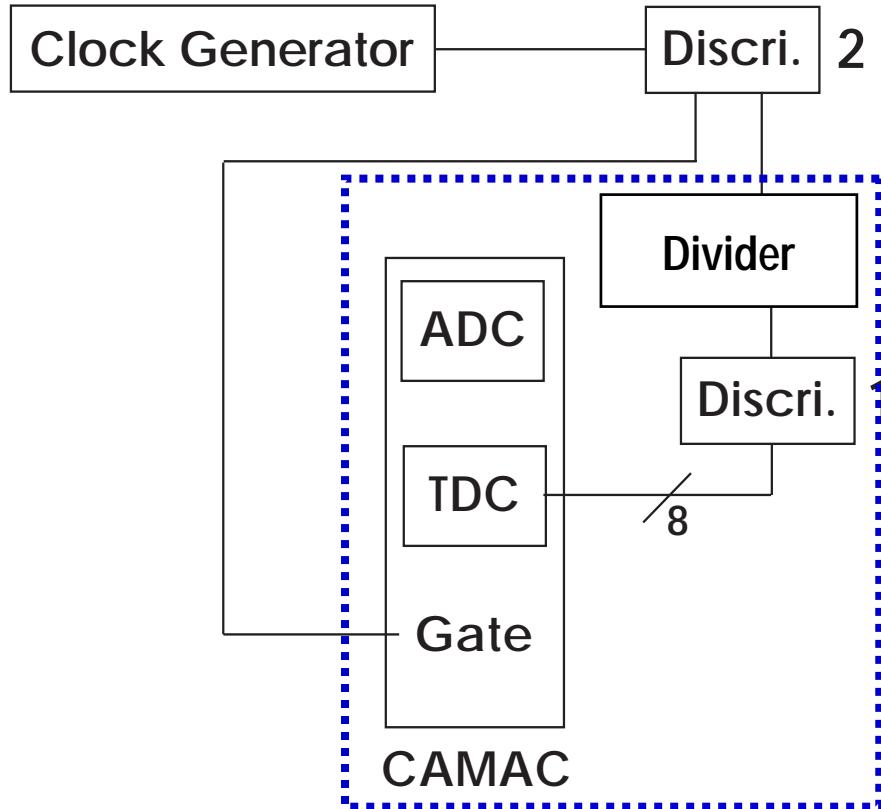
For short path, no chromaticity effect.

$$\sigma = 30-40 \text{ ps} / \sqrt{50} = 5-6 \text{ ps}$$

1. Points for TOF counter (continue)



矩形波で測定
測定回路の寄与 = 8.8psec



Footnote: TOF精度を決める要因。回路系の精度(実測値 = 7-9 psec)。ビームテストではatt.&は不要。

2. Measurements

L16-TOF

NIM submitted by Y.Enari et al, Cross-Talk of a Multi-Anode PMT and Attainment of a $\sigma \sim 10$ ps TOF counter

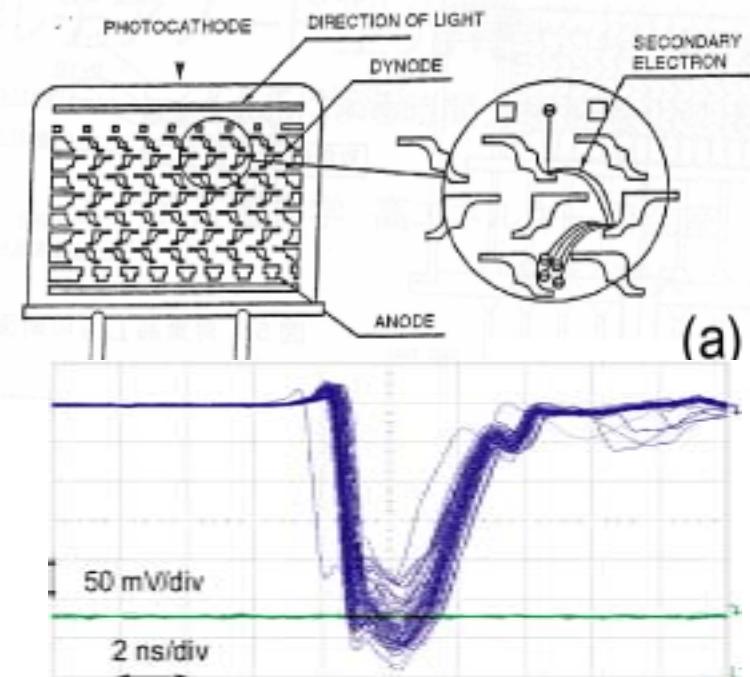
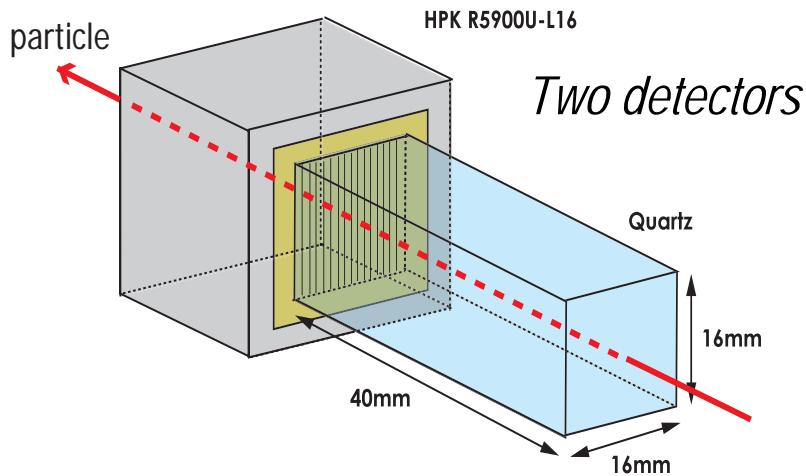
TTS=80 ps, $N\gamma = 120-160 / 4$ cm quartz,

16 independent measures

$$\sigma_0 = 80/\sqrt{9} \text{ (photons/channel)} / \sqrt{16} = 7 \text{ ps}$$

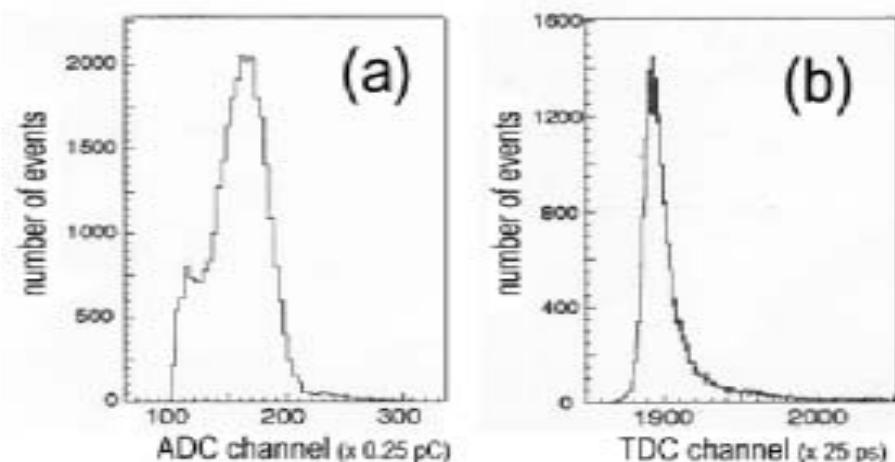
$\sigma_{\text{expected}} = 11 \text{ ps}$

including circuit fluctuation of 9 ps.

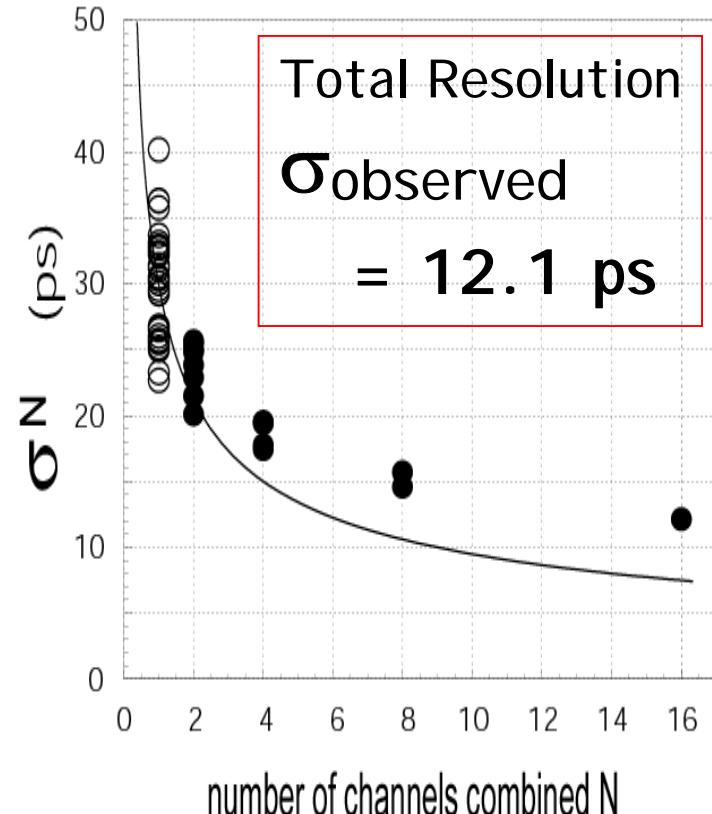
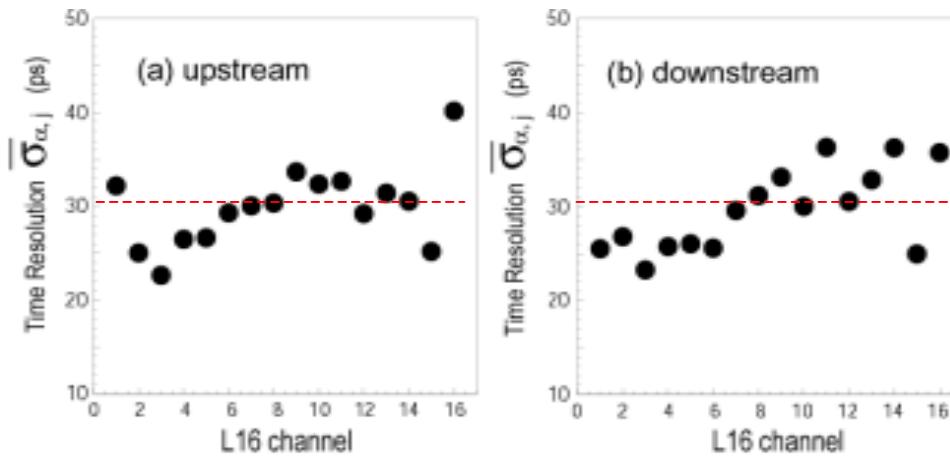


$TOF = TOF_1 - TOF_2$, where

$$TOF_\alpha = \frac{\sum_{j=1}^{16} tof_{\alpha,j}}{16}, \quad \sigma_\alpha = \sqrt{\frac{\sum_{j=1}^{16} \sigma_{\alpha,j}^2}{16}}$$



Single channel Resolution $\sigma = 30$ ps



Footnote: ビームテストのデータ、各チャンネル分解能 = 30 psec 16チャネルでは12.1 psec。

Intrinsic resolution and systematic uncertainty

In order to examine the origin of the systematic uncertainty, we suppose the measured time-of-flight ($tof_{\alpha,j}$) to be composed of two components: the subjective time ($t_{\alpha,j}$) and the systematic uncertainties (t_x), as

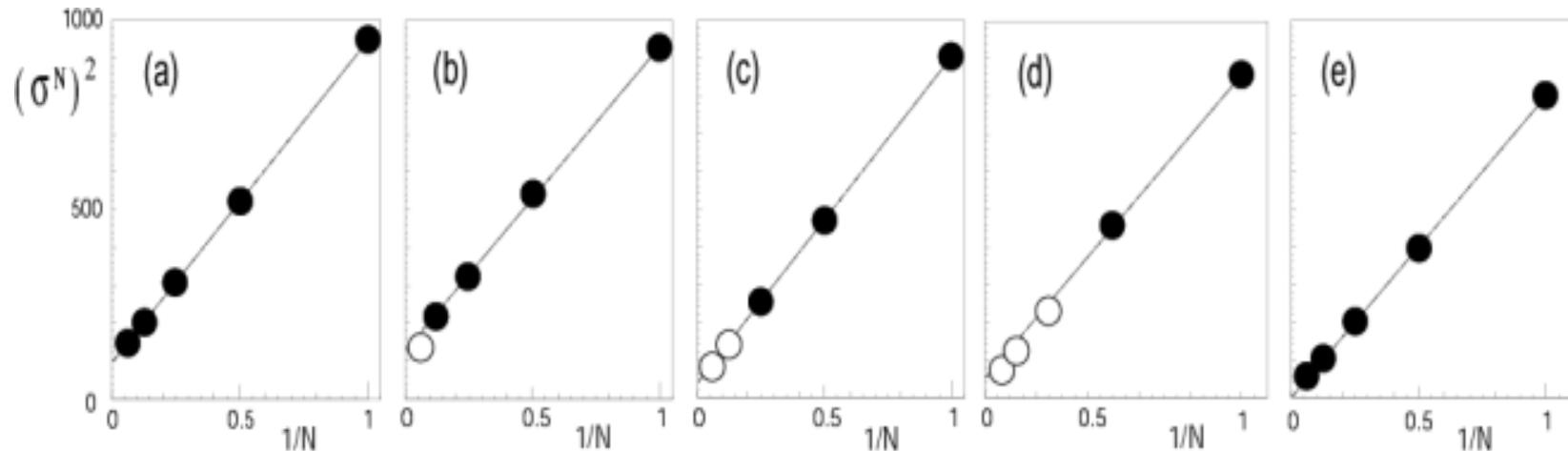
$$tof_{\alpha,j} = t_{\alpha,j} + (t_{32} + t_{16} + t_8 + t_4 + t_2), \quad (8)$$

where t_{32} is the uncertainty common to all $32 = 2 \times 16$ channels; t_{16} is common to $j = 1\text{-}16$ channels, but different at each counter, $\alpha = 1$ or 2 ; t_8 is common to $j = 1\text{-}8$ and also $9\text{-}16$ channels, but different at 8 individual channels and each counter; t_4 is common to $j = 1\text{-}4$, $5\text{-}8$, $9\text{-}12$ and $13\text{-}16$ channels, but different at 4 individual channels and each counter; t_2 is common to $j = 1\text{-}2$, $3\text{-}4$, ..., $15\text{-}16$ channels, but different at 2 individual channels and each counter.

σ^N can be expressed as

$$(\sigma^N)^2 = \frac{a^2}{N} + b^2, \quad (9)$$

where a is the time resolution of a single channel, and b is the contribution of the systematic uncertainty. An adequate combination of two channels cancels certain t_x 's in the time-of-flight $tof_{\alpha,j} - tof_{\beta,k}$, and its N dependence of $(\sigma^N)^2$ provides a and b .



Footnote: Systematic errorの評価。 $j = 16$ と $j = 4$ での寄与が大きい。

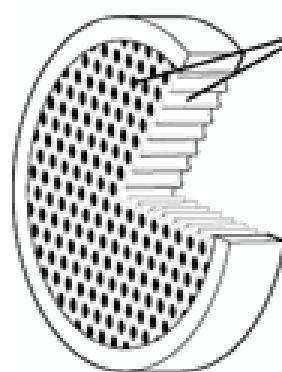
2. Measurements

MCP-TOF

NIM A528 (2004) 763-775, by M. Akatsu et al, "MCP-PMT timing property for single photons"

MCP-PMT	HPK6	BINP10	HPK10	Burle25
diameter of MCP-PMT (mm)	45°	30.5°	52°	71×71 ^{±1}
diameter of effective size (mm)	11°	18°	25°	50×50 ^{±2}
photocathode	bialkali	multialkali	bialkali	bialkali
gaps (mm)	2 / 0.03 / 1	0.2 / 0.1 / 1.2	1.1 / 0 / 0.94	6.4 / 0.032 / -
D ^{±3} (μm)	6	10	10	25
$\alpha = L/D$ ^{±3}	40	40	43	40
bias angle (°)	13	5	12	10
max. voltage (kV)	3.6	3.2	3.6	2.5
divider ratio	2 : 4 : 1	3.4 : 30 : 1	2 : 4 : 1	1 : 10 : 1
gain	2×10^6	$\sim 10^6$	$\sim 10^5$	6×10^5

M C P の構造

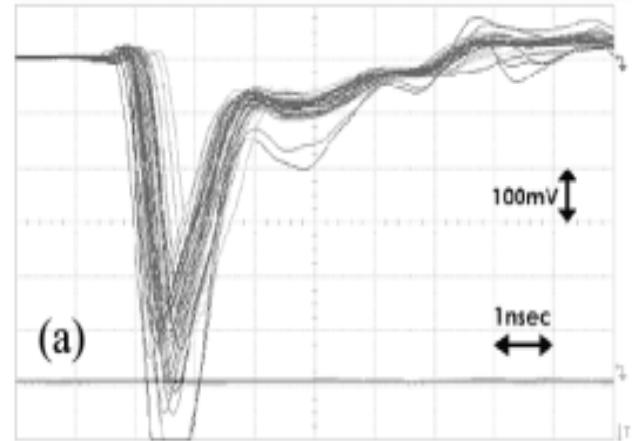
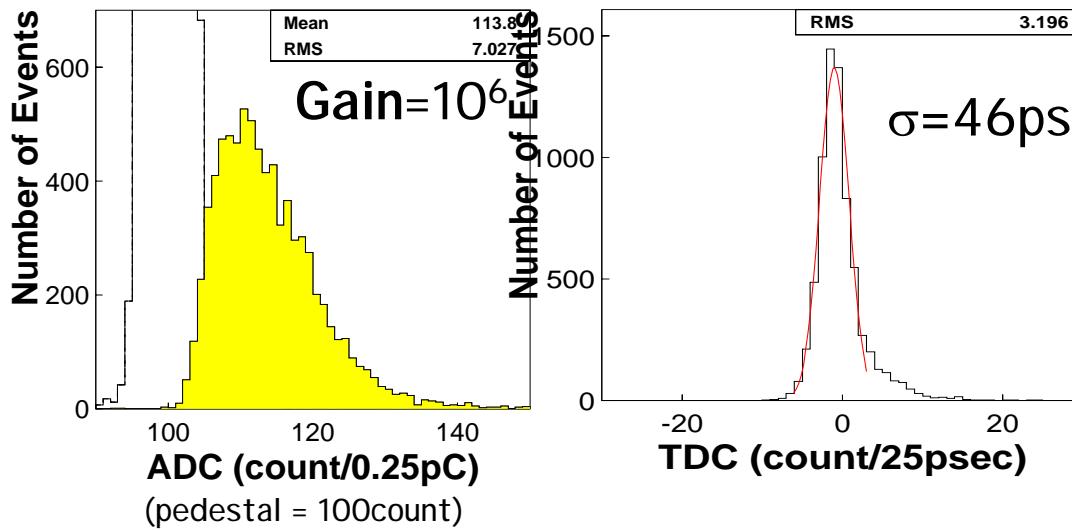


MCP(Micro-Channel Plate)

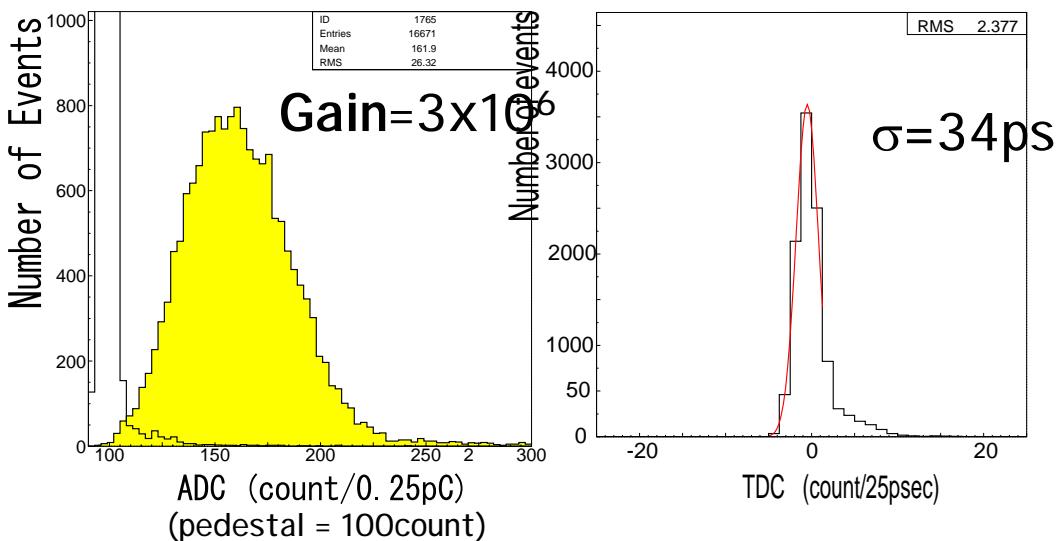


2. Measurements / MCP spectra

- HPK R3809U-50-25X



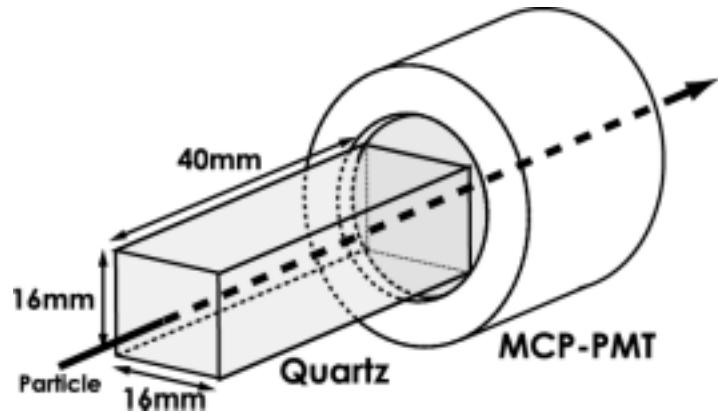
- BI NP N4963



(1光子照射,HV:3.2kV)

Footnote: ADC & TDC spectra

2. Measurements / TOF by HPK10

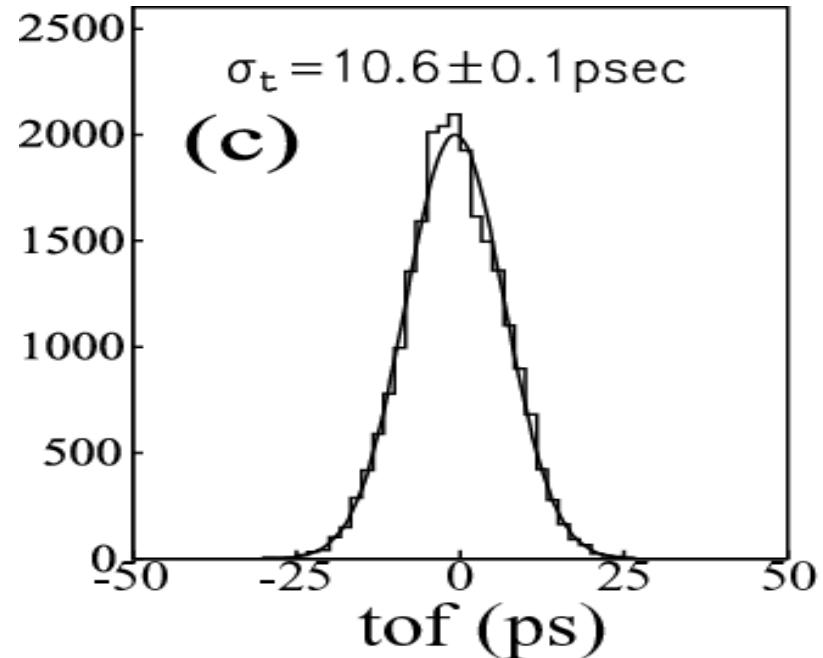


$TTS = 46 \text{ ps}$, $N\gamma = 200/4 \text{ cm quartz}$,
 $\sigma_0 = 46/\sqrt{200} = 3 \text{ ps}$

$\sigma_{\text{expected}} = 9 \text{ ps}$

including circuit fluctuation of 9 ps.

$\sigma_{\text{observed}} = 10.6 \text{ ps}$



With different TTS [L16(TTS=80 ps) & MCP(TTS=46 ps)] and similar N 's, $\sigma_{\text{observed}} = 11-12 \text{ ps}$ is attained, where the circuit fluctuations (7-9 ps) dominate the ambiguity.

Summary

1. TOF resolution = **10 ps achieved !**
2. K/pi separation at Belle (Belle is a relatively small spectrometer)
~ 4 σ at 4 GeV/c
3. Issues to be solved:
 - (1) MCP-PMT **lifetime**
 - (2) enlargement of radiator
 - (3) **precise circuit**

K/ π separation (σ) for Belle with 10 ps

